



# 600V, 20A, Trench FS II Fast IGBT

## General Description:

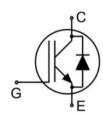
Using MJ's proprietary trench design and advanced FS (Field Stop) second generation technology, the 600V Trench FSII IGBT offers superior conduction and switching performances, and easy parallel operation;

#### Features

- ◆ Trench FSII Technology offering
- ♦ Very low Vce (sat)
- High speed switching
- ◆ Positive temperature coefficient in V<sub>CE</sub> (sat)
- ◆ Very tight parameter distribution
- ♦ High ruggedness, temperature stable behavior

## Application

- ◆ Air Condition
- Inverters
- ♠ Motor drives







TO-220F

## Package Marking and Ordering Information

Device	Device Package	Device Marking			
MJ20TD60BF	TO-220F	MJ20TD60BF			

### Absolute Maximum Ratings (Tc=25°C unless otherwise noted)

Parameter	Symbol	Value	Units
Collector-Emitter Voltage	Vces	600	V
Gate- Emitter Voltage	VGES	±30	V
Collector Current	Ic	40	А
Collector Current @Tc = 100 °C	Ic	20	А
Pulsed Collector Current, tp limited by T <sub>jmax</sub>	Cplus	60	А
turn off safe operating area, VcE=600V, Tj=150°C	-	60	Α
Diode Continuous Forward Current @Tc = 100 °C	lF	20	А
Diode Maximum Forward Current	IFM	60	А
Power Dissipation @ Tc = 25°C	Po	34.5	W
Power Dissipation @Tc = 100 °C	Po	17.2	W
Operating Junction and Storage Temperature Range	TJ,Tstg	-55 to +175	°C
Maximum Temperature for Soldering	TL	260	°C
Short circuit withstand time V <sub>GE</sub> =15.0V, V <sub>CC</sub> ≤400V, Allowed number of short circuits<1000Time between short circuits:≥1.0s,Tj≤150°C	tsc	5	us





### Thermal Characteristic

Parameter	Symbol	Value	Units
Thermal Resistance, Junction to case for IGBT	Rejc	4.34	°C/W
Thermal Resistance, Junction to case for Diode	Rejc	3.9	°C/W
Thermal Resistance, Junction to Ambient	Reja	78	°C/W

# Electrical Characteristics (Tc=25°C unless otherwise noted)

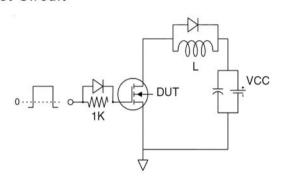
December	Symbol	T		Value				
Parameter	Symbol Test Conditions		Min	Тур	Max	Units		
Static Characteristics								
Collector-Emitter Breakdown Voltage	V(BR)CES	Vge=0V,Ice=1mA		600	_	-	V	
Collector-Emitter Leakage Current	Ices	V <sub>GE</sub> =0V,\	/ce=600V	-	-	4	uA	
Gate to Emitter Forward Leakage	IGES(F)	V <sub>GE</sub> =+30	V,VcE=0V	-	-	100	nA	
Gate to Source Reverse Leakage	IGES(R)	V <sub>GE</sub> =-30	V,VcE=0V	-	-	100	nA	
Collector-Emitter Saturation Voltage	VcE(sat)	Ic=20A	Tj=25°C	-	1.7	1.9	V	
Collector-Ethlitter Saturation Voltage	V CE(sat)	V <sub>GE</sub> =15V	Tj=100°C	-	1.9	-	V	
Gate Threshold Voltage	V <sub>GE(th)</sub>	Ic=1mA	, V <sub>CE</sub> =V <sub>GE</sub>	4.0	-	6.0	V	
Dynamic Characteristics								
Input Capacitance	Cies	Vce=25V,Vge=0V, f=1MHz		-	2580	-	pF	
Output Capacitance	Coss			-	48	-	pF	
Reverse Transfer Capacitance	Crss			-	26	-	pF	
Total Gate Charge	$Q_g$	Vcc=480V, Ic=20A VgE=15V VgE=15V,Vcc≤400V, tsc≤5us,Tj≤150°C		-	97	-	nC	
Gate to Emitter Charge	Qge			-	17	-	nC	
Gate to Collector Charge	Qgc			-	37	-	nC	
Short circuit collector current Max.1000 short circuits Time between short circuits: ≥1.0s	Ic(sc)			-	130	-	А	
Switching Characteristics								
Turn-on Delay Time	t <sub>d</sub> (ON)			-	18	-	ns	
Rise Time	tr			-	16	-	ns	
Turn-Off Delay Time	t <sub>d(OFF)</sub>	Vcc=400V,Ic=10A V <sub>GE</sub> =0/15V, R <sub>g</sub> =25Ω Inductive Load		-	164	-	ns	
Fall Time	tr			-	15	-	ns	
Turn-On Switching Loss	Eon			-	0.43	-	mJ	
Turn-Off Switching Loss	Eoff			-	0.17	-	mJ	
Total Switching Loss	Ets			_	0.60	-	mJ	



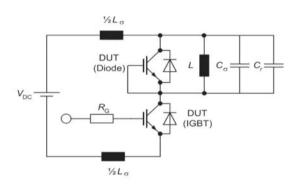
# Electrical Characteristics of the Diode (Tc= 25°C unless otherwise specified):

Doromotor	Symbol	Toot Conditions	Rating			Llmita
Parameter	Symbol	Test Conditions	Min	Тур	Max	Units
Diode Forward Voltage	V <sub>FM</sub>		_	1.45	1.7	V
Reverse Recovery Time	Tm		_	182	-	ns
Diode Peak Reverse Recovery Current	urrent IRRM I=20A,di/dt=20	I <sub>F</sub> =20A,di/dt=200A/uS	-	5.3	-	А
Reverse Recovery Charge	Qrr		-	0.5	-	uC
Pulse width ttp≤380μs,δ≤2%						'

### Test Circuit

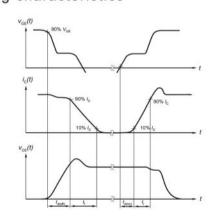


Gate Charge Test Circuit

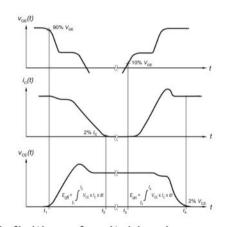


Switch Time Test Circuit

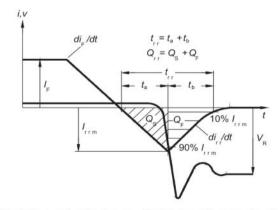
## Switching characteristics



definition of switching times



definition of switching losses

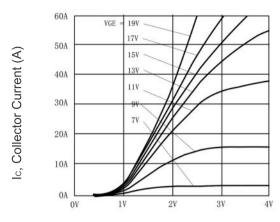


Definition of diode switching characteristics



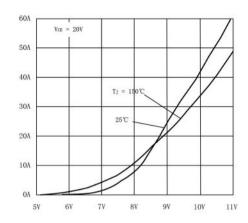


### Typical Electrical and Thermal Characteristics



Vce, Collector-Emitter Voltage (V)
Figure 1 Output Characteristics

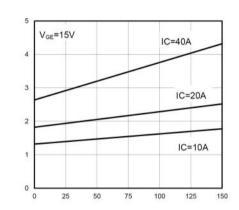
Ic, Collector Current (A)



V<sub>GE</sub>, Gate-Emitter Voltage (V)

Figure 2 Transfer Characteristics

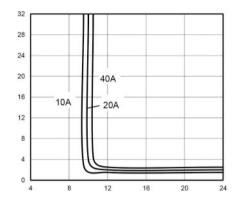
VcE, Collector-Emitter Saturation Voltage (V)



T<sub>J</sub>, Junction Temperature (°C)

Figure 3 V<sub>CEsat</sub> vs. Case Temperature

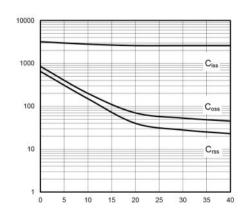




Vge, Gate-Emitter Voltage (V)

Figure 4 Saturation Voltage vs. VgE

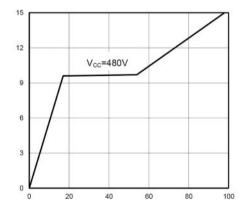
Capacitance (pF)



Vce, Collector-Emitter Voltage (V)

Figure 5 Capacitance Characteristics

VGE, Gate-Emitter Voltage (V)



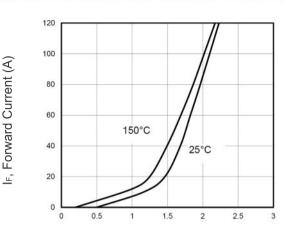
QG, Total Gate Charge (nC)

Figure 6 Gate charge waveform

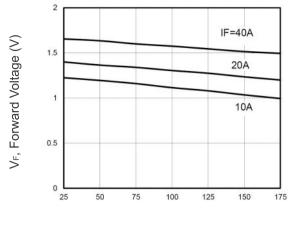


Ic, Collector Current (A)

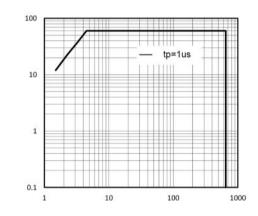
## Typical Electrical and Thermal Characteristics (continued)



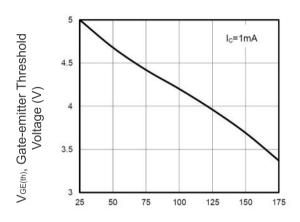
V<sub>F</sub>, Forward Voltage (V)
Figure 7 Forward Characteristics



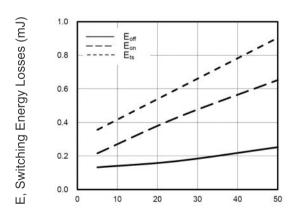
TJ, Junction Temperature (°C)
Figure 8 VF vs. Temperature



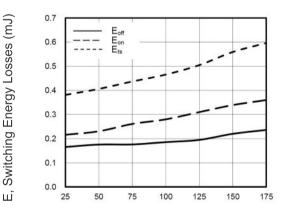
Vce, Collector-Emitter Voltage (V)
Figure 9 Forward Bias Safe Operating



TJ, Junction Temperature (°C)
Figure 10 Gate-emitter Threshold Voltage as a Function of Junction Temperature



 ${\sf R}_{\sf G}, \, {\sf Gate \ Resistor} \, (\Omega)$  Figure 11 Typical Switching Times as a Function of Gate Resistor



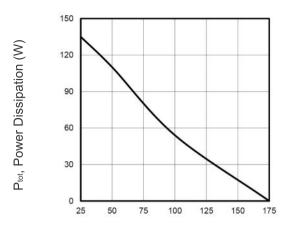
TJ, Junction Temperature (°C)
Figure 12 Typical Switching Times as a
Function of Junction Temperature



Vce, Collector-Emitter Voltage (V)

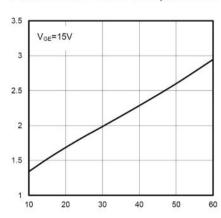


## Typical Electrical and Thermal Characteristics (continued)



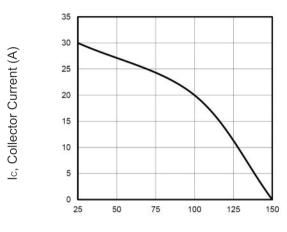
Tc, Case Temperature (°C)

Figure 13 Power Dissipation as a Function of Case Temperature



Ic, Collector Current (A)

Figure 15 Typical Collector-emitter Saturation Voltage as a function of Collector Current

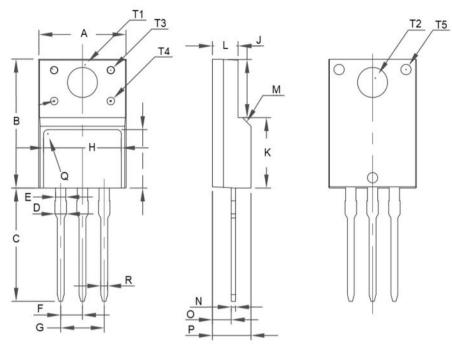


Tc, Collector-Emitter Case Temperature (°C)
Figure 14 Current Derating





# TO-220F Package Information



Cumahal	Dimensions	In Millimeters	Dimensions In Inches		
Symbol	Min.	Max.	Min.	Max.	
Α	9.96	10.36	0.39	0.41	
В	15.67	16.07	0.62	0.63	
С	13.14	13.54	0.52	0.53	
D	1.20	1.40	0.05	0.06	
E	1.20	BSC	0.05	BSC	
F	2.54	BSC	0.10	BSC	
G	5.08	BSC	0.20	BSC	
Н	7.60	8.00	0.30	0.31	
1	7.10	7.50	0.28	0.30	
J	6.48	6.88	0.26	0.27	
K	8.99	9.39	0.35	0.37	
L	2.34	2.74	0.09	0.11	
M	45	45°		BSC	
N	0.49	0.52	0.02	0.02	
0	2.15	2.55	0.08	0.10	
Р	4.50	4.90	0.18	0.19	
Q	0.			2 BSC	
R	0.77	0.83	0.03	0.03	
S	4°	5°	0.16	0.20	
T1	1 3.45 BSC 2 3.18 BSC		0.14 BSC		
T2			0.13 BSC 0.06 BSC		
Т3					
T4	T4 1.20 BSC 0.05 BSC			BSC	
T5	1.50	BSC	0.06 BSC		





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